

Mobile SDRAM

M52D256328A (2F)

2M x 32 Bit x 4 Banks

Mobile Synchronous DRAM

FEATURES

- 1.8V power supply
- LVCMOS compatible with multiplexed address
- Four banks operation
- MRS cycle with address key programs
 - CAS Latency (3)
- Burst Length (1, 2, 4, 8 & full page)
- Burst Type (Sequential & Interleave)
- EMRS cycle with address
- All inputs are sampled at the positive going edge of the system clock
- Special function support
- PASR (Partial Array Self Refresh)
- TCSR (Temperature Compensated Self Refresh)
- DS (Driver Strength)
- DQM for masking
- Auto & self refresh
- 64ms refresh period (4K cycle)

GENERAL DESCRIPTION

The M52D256328A is 268,435,456 bits synchronous high data rate Dynamic RAM organized as 4 x 2,097,152 words by 32 bits. Synchronous design allows precise cycle controls with the use of system clock I/O transactions are possible on every clock cycle. Range of operating frequencies, programmable burst lengths and programmable latencies allow the same device to be useful for a variety of high bandwidth, high performance memory system applications.

BALL CONFIGURATION (TOP VIEW)

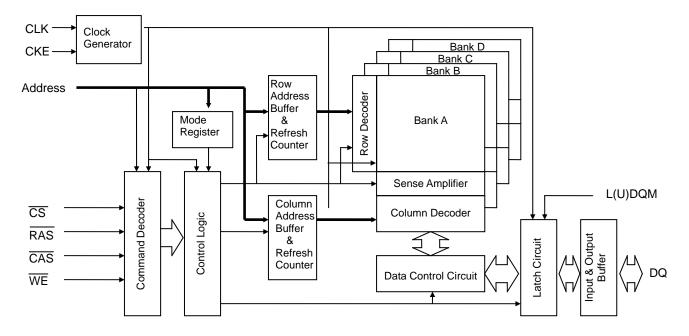
(BGA 90, 8mmX13mmX1.2mm Body, 0.8mm Ball Pitch)

	1	2	3	4	5	6	7	8	9
А	DQ26	DQ24	VSS				VDD	DQ23	DQ21
В	DQ28	VDDQ	VSSQ				VDDQ	VSSQ	DQ19
С	VSSQ	DQ27	DQ25				DQ22	DQ20	VDDQ
D	VSSQ	DQ29	DQ30				DQ17	DQ18	VDDQ
Е	VDDQ	DQ31	NC				NC	DQ16	VSSQ
F	VSS	DQM3	A3				A2	DQM2	VDD
G	A4	A5	A6				A10	A0	A1
н	A7	A8	NC				NC	BA1	A11
J	CLK	CKE	A9				BA0	CS	RAS
к	DQM1	NC	NC				CAS	WE	DQM0
L	VDDQ	DQ8	VSS				VDD	DQ7	VSSQ
М	VSSQ	DQ10	DQ9				DQ6	DQ5	VDDQ
Ν	VSSQ	DQ12	DQ14				DQ1	DQ3	VDDQ
Ρ	DQ11	VDDQ	VSSQ				VDDQ	VSSQ	DQ4
R	DQ13	DQ15	VSS				VDD	DQ0	DQ2

ORDERING INFORMATION

Product ID	Max Freq.	Package	Comments		
M52D256328A-6BG2F	166MHz	90 Ball FBGA	Pb-free		
M52D256328A-7BG2F	143MHz	90 Ball FBGA	Pb-free		

FUNCTIONAL BLOCK DIAGRAM



BALL FUNCTION DESCRIPTION

PIN	NAME	INPUT FUNCTION
CLK	System Clock	Active on the positive going edge to sample all inputs
CS	Chip Select	Disables or enables device operation by masking or enabling all inputs except CLK , CKE and DQM
СКЕ	Clock Enable	Masks system clock to freeze operation from the next clock cycle. CKE should be enabled at least one cycle prior new command. Disable input buffers for power down in standby.
A0 ~ A11	Address	Row / column address are multiplexed on the same pins. Row address : RA0~RA11, column address : CA0~CA8
BA0 , BA1	Bank Select Address	Selects bank to be activated during row address latch time. Selects bank for read / write during column address latch time.
RAS	Row Address Strobe	Latches row addresses on the positive going edge of the CLK with \overrightarrow{RAS} low. Enables row access & precharge.
CAS	Column Address Strobe	Latches column address on the positive going edge of the CLK with \overline{CAS} low. Enables column access.
WE	Write Enable	Enables write operation and row precharge. Latches data in starting from \overline{CAS} , \overline{WE} active.
DQM0 ~ DQM3	Data Input / Output Mask	Makes data output Hi-Z, tsHz after the clock and masks the output. Blocks data input when DQM active.
DQ0 ~ DQ 31	Data Input / Output	Data inputs / outputs are multiplexed on the same pins.
V _{DD} / V _{SS}	Power Supply / Ground	Power and ground for the input buffers and the core logic.
V _{DDQ} / V _{SSQ}	Data Output Power / Ground	Isolated power supply and ground for the output buffers to provide improved noise immunity.
NC	No Connection	This pin is recommended to be left No Connection on the device.

ABSOLUTE MAXIMUM RATINGS

PARAMETER	SYMBOL	VALUE	UNIT
Voltage on any pin relative to Vss	Vin, Vout	-1.0 ~ 2.6	V
Voltage on VDD supply relative to VSS	Vdd, Vddq	-1.0 ~ 2.6	V
Operation ambient temperature	Та	0 ~ +70	°C
Storage temperature	Тѕтс	-55 ~ +150	°C
Power dissipation	PD	1	W
Short circuit current	los	50	mA

Note: Permanent device damage may occur if ABSOLUTE MAXIMUM RATING are exceeded. Functional operation should be restricted to recommended operating condition.

Exposure to higher than recommended voltage for extended periods of time could affect device reliability.

DC OPERATING CONDITION

Recommended operating conditions (Voltage referenced to $V_{SS} = 0V$)

PARAMETER	SYMBOL	MIN	TYP	МАХ	UNIT	NOTE
Supply voltage	Vdd, Vddq	1.7	1.8	1.95	V	1
Input logic high voltage	Vih	$0.8 \text{ x } V_{\text{DDQ}}$	1.8	V _{DDQ} +0.3	V	2
Input logic low voltage	VIL	-0.3	0	0.3	V	3
Output logic high voltage	Vон	Vddq-0.2	-	-	V	Іон = -0.1mA
Output logic low voltage	Vol	-	-	0.2	V	IoL = 0.1mA
Input leakage current	lı∟	-2	-	2	μA	4

Note: 1. under all conditions, V_{DDQ} must be less than or equal to V_{DD} .

2. V_{IH} (max) = 2.2V. The overshoot voltage duration is \leq 3ns.

3. V_{IL} (min) = -1.0V. The undershoot voltage duration is \leq 3ns.

4. Any input $0V \leq V_{IN} \leq V_{DDQ}$.

Input leakage currents include Hi-Z output leakage for all bi-directional buffers with tri-state outputs.

CAPACITANCE (V_{DD} = 1.8V, T_A = 25 °C , f = 1MHz)

PARAMETER	SYMBOL	MIN	ΜΑΧ	UNIT
Input capacitance (A0 ~ A11, BA0 ~ BA1)	CIN1	1	5	pF
Input capacitance (CLK, CKE, CS, RAS, CAS, WE & DQM0~DQM3)	Cin2	1	5	pF
Data input/output capacitance (DQ0 ~ DQ31)	Соит	1	6	pF

DC CHARACTERISTICS

Recommended operating condition unless otherwise noted

				Vers	sion		
Parameter	Symbol	Tes	t Condition	-6	-7	Unit	Note
Operating Current (One Bank Active)	Icc1	Burst Length = 1 trc ≥ trc (min), tcc ≥	tcc (min), lo∟= 0mA	70	60	mA	1
Precharge Standby	ICC2P	CKE ≤ VIL(max), tcc	=15ns	60	00	uA	
Current in power-down mode	ICC2PS	CKE ≤ Vı∟(max), CLł	$K \leq V_{IL}(max), tcc = \infty$	60	uA		
Precharge Standby Current in non	Ісс2н		\geq VIH(min), tcc =10ns anged one time during 20ns		7	mA	
power-down mode	ICC2NS	CKE≥V⊮(min), CLK Input signals are sta	$X \leq V_{IL}(max), t_{CC} = \infty$	2	4	mA	
Active Standby Current	Іссзр	CKE ≤ VIL(max), tcc	=15ns	4	mA		
in power-down mode	Іссзря	$CKE \leq V \parallel (max), C$	$LK \le V_{IL}(max), tcc = \infty$	4	IIIA		
Active Standby Current in non power-down mode	Іссзи		\geq VIH(min), tcc=15ns anged one time during 2clks p-0.2V or \leq 0.2V	1	5	mA	
(One Bank Active)	Іссзия	CKE≥V⊮ (min), CLI Input signals are sta		2	4	mA	
Operating Current (Burst Mode)	Icc4	Io∟= 0mA, Page Burs All Bank Activated, to		90	80	mA	1
Refresh Current	Icc5	$t_{RFC} \ge t_{RFC}(min)$		110	95	mA	2
			TCSR range	45	75	°C	
			Full array	550	600		
			1/2 array	530	580		
Self Refresh Current	Icc6	CKE≤0.2V	1/4 array	510	560	uA	
			1/8 array	490	540		
			1/16 array	470	520	1	
Deep Power Down Current	Ісс7	CKE ≤ 0.2V		1	0	uA	

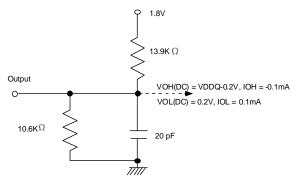
Note: 1.Measured with outputs open. Addresses are changed only one time during tcc(min).

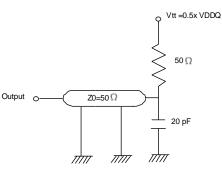
2.Refresh period is 64ms. Addresses are changed only one time during tcc(min).



AC OPERATING TEST CONDITIONS (VDD= 1.7V~1.95V)

Parameter	Value	Unit
Input levels (Vih/Vil)	0.9 x Vddq / 0.2	V
Input timing measurement reference level	0.5 x VDDQ	V
Input rise and fall time	tr / tf = 1 / 1	ns
Output timing measurement reference level	0.5 x VDDQ	V
Output load condition	See Fig.2	





(Fig.2) AC Output Load Circuit

(Fig.1) DC Output Load circuit

OPERATING AC PARAMETER

(AC operating conditions unless otherwise noted)

Paramete	r	Symbol	Vers	sion	Unit	Note
Faramete		Symbol	-6	-7	Onit	NOLE
Row active to row active de	lay	trrd(min)	12	14	ns	1
RAS to CAS delay		trcd(min)	18	21	ns	1
Row precharge time		trp(min)	18	21	ns	1
Row active time		tras(min)	42	42	ns	1
		tras(max)	1(us	-	
Row cycle time	@ Operating	trc(min)	60	63	ns	1
	@ Auto refresh	trfc(min)	80		ns	1,5
Last data in to new col. Add	ress delay	tco∟(min)	1		CLK	2
Last data in to row precharg	le	trdl(min)	2	2	CLK	2
Last data in to burst stop		tв⊳∟(min)		l	CLK	2
Col. Address to col. Address	s delay	tccp(min)		CLK	3	
Mode Register command to Command	tmrd(min)	2		CLK	-	
Refresh period(4,096 rows)	tref(max)	64		ms	6	
Number of valid output data				2	ea	4

Note: 1. The minimum number of clock cycles is determined by dividing the minimum time required with clock cycle time and then rounding off to the next higher integer.

- 3. Minimum delay is required to complete write.
- 4. All parts allow every cycle column address change.
- 5. In case of row precharge interrupt, auto precharge and read burst stop.
- The earliest a precharge command can be issued after a Read command without the loss of data is CL+BL-2 clocks 5. A new command may be given t_{RFC} after self refresh exit.
- 6. A maximum of eight consecutive AUTO REFRESH commands (with tRFCmin) can be posted to any given SDRAM, and the maximum absolute interval between any AUTO REFRESH command and the next AUTO REFRESH command is 8x15.6 μ s.)

AC CHARACTERISTICS (AC operating conditions unless otherwise noted)

Parameter	Symbol		-6		-7	Unit	Note
Farameter	Symbol	Min	Max	Min	Max	Unit	Note
CLK cycle time	tcc	6	1000	7	1000	ns	1
CLK to valid output delay	tsac		5.4		6	ns	1
Output data hold time	tон	2.3		2.5		ns	2
CLK high pulse width	tсн	2.5		2.5		ns	3
CLK low pulse width	tc∟	2.5		2.5		ns	3
Input setup time	tss	2		2		ns	3
Input hold time	tsн	1		1.5		ns	3
CLK to output in Low-Z	ts∟z	1		1		ns	2
CLK to output in Hi-Z	tsнz		5.4		6	ns	

*All AC parameters are measured from half to half.

Note: 1. Parameters depend on programmed CAS latency.

2. If clock rising time is longer than 1ns, (tr/2-0.5)ns should be added to the parameter.

3. Assumed input rise and fall time (tr & tf)=1ns.

If tr & tf is longer than 1ns, transient time compensation should be considered, i.e., [(tr+ tf)/2-1]ns should be added to the parameter.

SIMPLIFIED TRUTH TABLE

C	OMMAND		CKEn-1	CKEn	CS	RAS	CAS	WE	DQM	BA0 BA1	A10/AP	A11, A9~A0	Note
Register	Mode Regist Extended Mo set		Н	Х	L	L	L	L	х		OP CODE		
Refresh	Auto Refresh	Entry	н	H	L	L	L	н	х		х		3 3
	Refresh	Exit	L	Н	L H	H X	H X	H X	X X		х		3 3
Bank Active & Ro	ow Addr.		Н	Х	L	L	Н	Н	Х	V	Row A	Address	
Read &	Auto Prec	harge Disable									L	Column	4
Column Address	Auto Prec	harge Enable	н	Х	L	Н	L	Н	Х	V	н	Address (A0~A8)	4,5
Write &	Auto Prec	harge Disable									L	Column	4
Column Address	Auto Precharge Enable		Н	Х	L	Н	L	L	Х	V	н	Address (A0~A8)	4,5
Burst Stop			Н	Х	L	Н	Н	L	Х		Х		6
	Bank Sele	Bank Selection All Banks		X					V	V	L	х	
Precharge	All Banks			Х	LL	L	Н	L	Х	Х	Н		
		Entry	н	L	Н	Х	Х	Х	x				
Clock Suspend o Active Power Do		Entry		L	L	Н	Н	Н			Х		
Active 1 Ower Do	WITIMODE	Exit	L	Н	Х	Х	Х	Х	Х				
		Entry	н	L	Н	Х	Х	Х	х				
Precharge Powe	r Down Mode	•	11	L	L	Н	Н	Н	^				
Treenarge Tower	Downmode	Exit	L	н	Н	Х	Х	Х	x		Х		
DOM					L	H	Н	Н			N		-
DQM		Н		н	X X	Х	V	V		Х		7	
No Operating Co	mmand		н	Х	H L	X H	× H	X H	Х		Х		
		Entry	Н	L	L	н	н	L	Х				
Deep Power Dov	n Mode	Exit	L	Н	Х	Х	Х	Х	Х		Х		

(V = Valid, X = Don't Care. H = Logic High, L = Logic Low)

Note: 1.OP Code: Operating Code

A0~A11 & BA0~BA1: Program keys. (@ MRS). BA1=0 for MRS and BA1=1 for EMRS

2.MRS/EMRS can be issued only at all banks precharge state.

A new command can be issued after 2 CLK cycles of MRS/EMRS.

3.Auto refresh functions are as same as CBR refresh of DRAM.

The automatical precharge without row precharge of command is meant by "Auto".

Auto/self refresh can be issued only at all banks idle state.

4.BA0~BA1: Bank select addresses.

If both BA0 and BA1 are "Low" at read, write, row active and precharge, bank A is selected.

If both BA0 is "Low" and BA1 is "High" at read, write, row active and precharge, bank B is selected.

If both BA0 is "High" and BA1 is "Low" at read, write, row active and precharge, bank C is selected.

If both BA0 and BA1 are "High" at read, write, row active and precharge, bank D is selected

If A10/AP is "High" at row precharge, BA0 and BA1 is ignored and all banks are selected.

5. During burst read or write with auto precharge, new read/write command can not be issued.

Another bank read/write command can be issued after the end of burst.

New row active of the associated bank can be issued at t_{RP} after the end of burst.

6.Burst stop command is valid at every burst length.

7.DQM sampled at positive going edge of a CLK and masks the data-in at the very CLK (write DQM latency is 0), but makes Hi-Z state the data-out of 2 CLK cycles after.(Read DQM latency is 2)

MODE REGISTER FIELD TABLE TO PROGRAM MODES

Register Programmed with MRS

Address	BA0	BA1	A11~A10/AP	A9	A8~A7	A6	A5	A4	A3	A2	A1	A0
Function	0	0	RFU	W.B.L	ТМ	CAS Latency		BT	Bu	rst Len	gth	

Test Mode			CAS Latency			Bu	rst Type	Burst Length					
A 8	A7	Туре	A6	A5	A4	Latency	A3	Туре	A2	A1	A0	BT = 0	BT = 1
0	0	Mode Register Set	0	0	0	Reserved	0	Sequential	0	0	0	1	1
0	1	Reserved	0	0	1	Reserved	1	Interleave	0	0	1	2	2
1	0	EMRS	0	1	0	Reserved			0	1	0	4	4
1	1	Reserved	0	1	1	3			0	1	1	8	8
	Write	Burst Length	1	0	0	Reserved			1	0	0	Reserved	Reserved
A9		Length	1	0	1	Reserved			1	0	1	Reserved	Reserved
0		Burst	1	1	0	Reserved			1	1	0	Reserved	Reserved
1		Single Bit	1	1	1	Reserved			1	1	1	Full Page	Reserved

Full Page Length: 512

Note:

RFU (Reserved for future use) should stay "0" during MRS cycle.
 If A9 is high during MRS cycle, "Burst Read Single Bit Write" function will be enabled.

3. The full column burst (512 bit) is available only at sequential mode of burst type.



EXTENDED MODE REGISTER SET (EMRS)

The extended mode register stores for selecting PASR; DS. The extended mode register set must be done before any active command after the power up sequence. The extended mode register is written by asserting low on \overline{CS} , \overline{RAS} , \overline{CAS} , \overline{WE} and high on BA1,low on BA0(The SDRAM should be in all bank precharge with CKE already high prior to writing into the extended more register). The state of address pins

A0~An in the same cycle as \overline{CS} , \overline{RAS} , \overline{CAS} , \overline{WE} going low is written in the extended mode register. Refer to the table for specific codes.

The extended mode register can be changed by using the same command and clock cycle requirements during operations as long as all banks are in the idle state.

Internal Temperature Compensated Self Refresh (TCSR)

Note:

- 1. In order to save power consumption, Mobile-DRAM includes the internal temperature sensor and control units to control the self refresh cycle automatically according to the device temperature.
- 2. If the EMRS for external TCSR is issued by the controller, this EMRS code for TCSR is ignored.

BA1	BA0	A11 ~ A8	A7	A6	A5		A3	A2	A1	A0		ess bus	
1	0*	0*		DS			CSR		PASR		Exten	ded Mode	e Register Set
										Γ		A2-A0	Self Refresh Coverage
												000	Full array
												001	1/2 array (BA1=0)
												010	1/4 array
												010	(BA0=BA1=0)
												011	Reserved
											PASR	100	Reserved
												101	1/8 array
												101	$(BA1 = BA0 = Row Addr MSB^{**} = 0)$
												110	1/16 array
													(BA1 = BA0 = Row Addr 2 MSB = 0)
												111	Reserved
						l				-[Interna	al TCSR	
										–		A7-A5	Driver Strength
													Driver Strength
											DS	000	Full Strength
				—								001	1/2 Strength
												010	1/4 Strength
												011	1/8 Strength
												100	3/4 Strength

Note: * BA0 and A11~ A8 should stay "0" during EMRS cycle ** MSB: most significant bit

BURST SEQUENCE (BURST LENGTH = 4)

Initial A	Address		Segu	ential		Interleave					
A1	A0	Sequential Interleave									
0	0	0	1	2	3	0	1	2	3		
0	1	1	2	3	0	1	0	3	2		
1	0	2	3	0	1	2	3	0	1		
1	1	3	0	1	2	3	2	1	0		

BURST SEQUENCE (BURST LENGTH = 8)

Ini	tial Addr	ess		Sequential					Interleave									
A2	A1	A0		Sequential Interleave														
0	0	0	0	1	2	3	4	5	6	7	0	1	2	3	4	5	6	7
0	0	1	1	2	3	4	5	6	7	0	1	0	3	2	5	4	7	6
0	1	0	2	3	4	5	6	7	0	1	2	3	0	1	6	7	4	5
0	1	1	3	4	5	6	7	0	1	2	3	2	1	0	7	6	5	4
1	0	0	4	5	6	7	0	1	2	3	4	5	6	7	0	1	2	3
1	0	1	5	6	7	0	1	2	3	4	5	4	7	6	1	0	3	2
1	1	0	6	7	0	1	2	3	4	5	6	7	4	5	2	3	0	1
1	1	1	7	0	1	2	3	4	5	6	7	6	5	4	3	2	1	0

DEVICE OPERATIONS

CLOCK (CLK)

The clock input is used as the reference for all SDRAM operations. All operations are synchronized to the positive going edge of the clock. The clock transitions must be monotonic between VIL and VIH. During operation with CKE high all inputs are assumed to be in valid state (low or high) for the duration of setup and hold time around positive edge of the clock for proper functionality and Icc specifications.

CLOCK ENABLE(CKE)

The clock enable (CKE) gates the clock onto SDRAM. If CKE goes low synchronously with clock (set-up and hold time same as other inputs), the internal clock suspended from the next clock cycle and the state of output and burst address is frozen as long as the CKE remains low. All other inputs are ignored from the next clock cycle after CKE goes low. When all banks are in the idle state and CKE goes low synchronously with clock, the SDRAM enters the power down mode from the next clock cycle. The SDRAM remains in the power down mode ignoring the other inputs as long as CKE remains low. The power down exit is synchronous as the internal clock is suspended. When CKE goes high at least "1CLK + tss" before the high going edge of the clock, then the SDRAM becomes active from the same clock edge accepting all the input commands.

BANK ADDRESSES (BA0~BA1)

This SDRAM is organized as four independent banks of 2,097,152 words x 32 bits memory arrays. The BA0~BA1 inputs are latched at the time of assertion of \overline{RAS} and \overline{CAS} to select the bank to be used for the operation. The banks addressed BA0~BA1 are latched at bank active, read, write, mode register set and precharge operations.

ADDRESS INPUTS (A0~A11)

The 21 address bits are required to decode the 2,097,152 word locations are multiplexed into 12 address input pins (A0~A11). The 12 row addresses are latched along with \overline{RAS} and BA0~BA1 during bank active command. The 9 bit column addresses are latched along with \overline{CAS} , \overline{WE} and BA0~BA1 during read or with command.

NOP and DEVICE DESELECT

When \overline{RAS} , \overline{CAS} and \overline{WE} are high, The SDRAM performs no operation (NOP). NOP does not initiate any new operation, but is needed to complete operations which require more than single clock cycle like bank activate, burst read, auto refresh, etc. The device deselect is also a NOP and is entered by asserting \overline{CS} high. \overline{CS} high disables the command decoder so that \overline{RAS} , \overline{CAS} , \overline{WE} and all the address inputs are ignored.

MODE REGISTER SET (MRS)

The mode register stores the data for controlling the various operating modes of SDRAM. It programs the CAS latency, burst type, burst length, test mode and various vendor specific options to make SDRAM useful for variety of different applications. The default value of the mode register is not defined, therefore the mode register must be written after power up to operate the SDRAM. The mode register is written by asserting low on CS, RAS, CAS and WE (The SDRAM should be in active mode with CKE already high prior to writing the mode register). The state of address pins A0~A11 and BA0~BA1 in the same cycle as CS, RAS, CAS and WE going low is the data written in the mode register. Two clock cycles is required to complete the write in the mode register. The mode register contents can be changed using the same command and clock cycle requirements during operation as long as all banks are in the idle state. The mode register is divided into various fields into depending on functionality. The burst length field uses A0~A2, burst type uses A3, CAS latency (read latency from column address) use A4~A6, vendor specific options or test mode use A7~A8, A10~A11 and BA1~BA0. The write burst length is programmed using A9. A7~A8, A10/AP~A11 and BA0~BA1 must be set to low for normal SDRAM operation. Refer to the table for specific codes for various burst length, burst type and CAS latencies.



DEVICE OPERATIONS (Continued)

BANK ACTIVATE

The bank activate command is used to select a random row in an idle bank. By asserting low on RAS and CS with desired row and bank address, a row access is initiated. The read or write operation can occur after a time delay of tRCD (min) from the time of bank activation. tRCD is the internal timing parameter of SDRAM, therefore it is dependent on operating clock frequency. The minimum number of clock cycles required between bank activate and read or write command should be calculated by dividing tRCD (min) with cycle time of the clock and then rounding of the result to the next higher integer. The SDRAM has four internal banks in the same chip and shares part of the internal circuitry to reduce chip area, therefore it restricts the activation of four banks simultaneously. Also the noise generated during sensing of each bank of SDRAM is high requiring some time for power supplies to recover before another bank can be sensed reliably. trrd (min) specifies the minimum time required between activating different bank. The number of clock cycles required between different bank activation must be calculated similar to tRCD specification. The minimum time required for the bank to be active to initiate sensing and restoring the complete row of dynamic cells is determined by tras (min). Every SDRAM bank activate command must satisfy tras (min) specification before a precharge command to that active bank can be asserted. The maximum time any bank can be in the active state is determined by tRAS (max) and tRAS (max) can be calculated similar to tRCD specification.

BURST READ

The burst read command is used to access burst of data on consecutive clock cycles from an active row in an active bank. The burst read command is issued by asserting low on CS and RAS with WE being high on the positive edge of the clock. The bank must be active for at least tRCD (min) before the burst read command is issued. The first output appears in CAS latency number of clock cycles after the issue of burst read command. The burst length, burst sequence and latency from the burst read command is determined by the mode register which is already programmed. The burst read can be initiated on any column address of the active row. The address wraps around if the initial address does not start from a boundary such that number of outputs from each I/O are equal to the burst length programmed in the mode register. The output goes into high-impedance at the end of burst, unless a new burst read was initiated to keep the data output gapless. The burst read can be terminated by issuing another burst read or burst write in the same bank or the other active bank or a precharge command to the same bank. The burst stop command is valid at every page burst length.

BURST WRITE

The burst write command is similar to burst read command and is used to write data into the SDRAM on consecutive clock cycles in adjacent addresses depending on burst length and burst sequence. By asserting low on \overline{CS} , \overline{CAS} and $\overline{\text{WE}}$ with valid column address, a write burst is initiated. The data inputs are provided for the initial address in the same clock cycle as the burst write command. The input buffer is deselected at the end of the burst length, even though the internal writing can be completed yet. The writing can be complete by issuing a burst read and DQM for blocking data inputs or burst write in the same or another active bank. The burst stop command is valid at every burst length. The write burst can also be terminated by using DQM for blocking data and procreating the bank trdl after the last data input to be written into the active row. See DQM OPERATION also.

DQM OPERATION

The DQM is used mask input and output operations. It works similar to \overline{OE} during operation and inhibits writing during write operation. The read latency is two cycles from DQM and zero cycle for write, which means DQM masking occurs two cycles later in read cycle and occurs in the same cycle during write cycle. DQM operation is synchronous with the clock. The DQM signal is important during burst interrupts of write with read or precharge in the SDRAM. Due to asynchronous nature of the internal write, the DQM operation is critical to avoid unwanted or incomplete writes when the complete burst write is required. Please refer to DQM timing diagram also.

PRECHARGE

The precharge is performed on an active bank by asserting low on clock cycles required between bank activate and clock cycles required between bank activate and \overline{CS} , \overline{RAS} , \overline{WE} and A10/AP with valid BA0~BA1 of the bank to be procharged. The precharge command can be asserted anytime after tRAS (min) is satisfied from the bank active command in the desired bank. tRP is defined as the minimum number of clock cycles required to complete row precharge is calculated by dividing t_{RP} with clock cycle time and rounding up to the next higher integer. Care should be taken to make sure that burst write is completed or DQM is used to inhibit writing before precharge command is asserted. The maximum time any bank can be active is specified by tRAS (max). Therefore, each bank activates command. At the end of precharge, the bank enters the idle state and is ready to be activated again. Entry to power-down, Auto refresh, Self refresh and Mode register set etc. is possible only when all banks are in idle state.

DEVICE OPERATIONS (Continued)

AUTO PRECHARGE

The precharge operation can also be performed by using auto precharge. The SDRAM internally generates the timing to satisfy tRAS (min) and "tRP" for the programmed burst length and CAS latency. The auto precharge command is issued at the same time as burst write by asserting high on A10/AP, the bank is precharge command is asserted. Once auto precharge command is given, no new commands are possible to that particular bank until the bank achieves idle state.

ALL BANKS PRECHARGE

A11 banks can be precharged at the same time by using Precharge all command. Asserting low on \overline{CS} , \overline{RAS} , and

 $\overline{\text{WE}}$ with high on A10/AP after all banks have satisfied tras (min) requirement, performs precharge on all banks. At the end of trap after performing precharge all, all banks are in idle state.

AUTO REFRESH

The storage cells of SDRAM need to be refreshed every 64ms to maintain data. An auto refresh cycle accomplishes refresh of a single row of storage cells. The internal counter increments automatically on every auto refresh cycle to refresh all the rows. An auto refresh command is issued by

asserting low on $\overline{\text{CS}}$, $\overline{\text{RAS}}$ and $\overline{\text{CAS}}$ with high on CKE

and WE . The auto refresh command can only be asserted with all banks being in idle state and the device is not in power down mode (CKE is high in the previous cycle). The time required to complete the auto refresh operation is specified by t_{RFC} (min). The minimum number of clock cycles required can be calculated by driving t_{RFC} with clock cycle time and them rounding up to the next higher integer. The auto refresh operation is completed. The auto refresh is the preferred refresh mode when the SDRAM is being used for normal data transactions. The auto refresh cycle can be performed once in 15.6us.

SELF REFRESH

The self refresh is another refresh mode available in the SDRAM. The self refresh is the preferred refresh mode for data retention and low power operation of SDRAM. In self refresh mode, the SDRAM disables the internal clock and all the input buffers except CKE. The refresh addressing and timing is internally generated to reduce power consumption. The self refresh mode is entered from all banks idle state by asserting low on \overline{CS} , \overline{RAS} , \overline{CAS} and CKE with high on \overline{WE} . Once the self refresh mode is entered, only CKE state being low matters, all the other inputs including clock are ignored to remain in the refresh.

The self refresh is exited by restarting the external clock and then asserting high on CKE. This must be followed by NOP's for a minimum time of tRFC before the SDRAM reaches idle state to begin normal operation. 4K cycles of burst auto refresh is required immediately before self refresh entry and immediately after self refresh exit.

COMMANDS

Mode register set command

 $(\overline{CS}, \overline{RAS}, \overline{CAS}, \overline{WE}, BA1, BA0 = Low)$

The DRAM has a mode register that defines how the device operates. In this command, A0 through BA0 are the data input pins. After power on, the mode register set command must be executed to initialize the device. The mode register can be set only when all banks are in idle state. During 2CLK (t_{MRD}) following this command, the DRAM cannot accept any other commands.

CLK	
CKE	Н
CS	
RAS	
CAS	
WE	
0, BA1	
A10	
Add	

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BA0.

CLK

Fig. 1 Mode register set command

OLK	
CKE	Н
CS	
RAS	
CAS	
WE	
BA0	
BA1	
A10	Row
Add	Row

Fig. 2 Extended Mode register set command

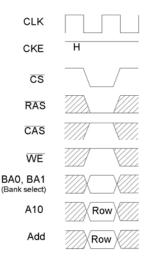


Fig. 3 Row address stroble and bank active command

Extended Mode register set command

 $(\overline{CS}, \overline{RAS}, \overline{CAS}, \overline{WE}, BA0 = Low; BA1 = High)$

The DRAM has an extended mode register that defines how to set PASR, DS.

Activate command

 $(\overline{CS}, \overline{RAS} = Low, \overline{CAS}, \overline{WE} = High)$

The DRAM has four banks, each with 4,096 rows. This command activates the bank selected by BA1 and BA0 (BS) and a row address selected by A0 through A11.

This command corresponds to a conventional DRAM's RAS falling.

Precharge command

$(\overline{CS}, \overline{RAS}, \overline{WE} = Low, \overline{CAS} = High)$
This command begins precharge operation of the bank selected by BA1 and BA0 (BS). When A10 is High, all banks are precharged, regardless of BA1 and BA0. When A10 is Low, only the bank selected by BA1 and BA0 is precharged. After this command, the DRAM can't accept the activate command to the precharging bank during tRP (precharge to activate command period).

This command corresponds to a conventional DRAM's RAS rising.

CLK		
CKE	Н	
CS		
RAS		
CAS		\mathbb{Z}
WE		\mathbb{Z}
, BA1 select)		
10 select)		\mathbb{Z}
Add		\mathbb{Z}

BA0, (Bank A (Precharge

Fig. 4 Precharge command

Write command

$(\overline{CS}, \overline{CAS}, \overline{WE} = Low, \overline{RAS} = High)$

If the mode register is in the burst write mode, this command sets the burst start address given by the column address to begin the burst write operation. The first write data in burst can be input with this command with subsequent data on following clocks.

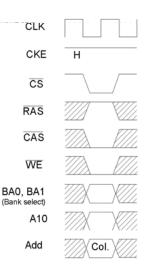


Fig. 5 Column address and write command

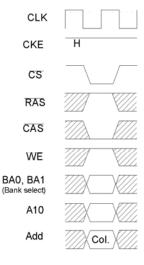


Fig. 6 Column address and read command

Read command

 $(\overline{CS}, \overline{CAS} = Low, \overline{RAS}, \overline{WE} = High)$

Read data is available after \overline{CAS} latency requirements have been met. This command sets the burst start address given by the column address.

CBR (auto) refresh command CLK Н CKE $(\overline{CS}, \overline{RAS}, \overline{CAS} = Low, \overline{WE}, CKE = High)$ CS This command is a request to begin the CBR refresh operation. The refresh address is generated internally. RAS Before executing CBR refresh, all banks must be precharged. After this cycle, all banks will be in the idle (precharged) state and ready for a row activate CAS command. During t_{RFC} period (from refresh command to refresh or activate command), the DRAM WE cannot accept any other command. BA0, BA1 (Bank select) A10 Add

Fig. 7 Auto refresh command

	CLK	
Self refresh entry command	CKE	
$(\overline{CS}, \overline{RAS}, \overline{CAS}, CKE = Low, \overline{WE} = High)$	CS	
After the command execution, self refresh operation continues while CKE remains low. When CKE goes to high, the DRAM exits the self refresh mode.	RAS	
During self refresh mode, refresh interval and refresh operation are performed internally, so there is no need for external control.	CAS	
Before executing self refresh, all banks must be precharged.	WE	
	BA0, BA1 (Bank select)	
	A10	
	Add	
	•	Self refresh entry command

Purst stop command	CLK		
Burst stop command	CKE	Н	
$(\overline{CS}, \overline{WE} = Low, \overline{RAS}, \overline{CAS} = High)$	CS		
This command terminates the current burst operation. Burst stop is valid at every burst length.	RAS		F
	CAS		F
	WE	\boxtimes	ŀ

BA0, BA1 (Bank select)

Add

A10

Fig. 9 Burst stop command

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No operation

 $(\overline{CS} = Low, \overline{RAS}, \overline{CAS}, \overline{WE} = High)$

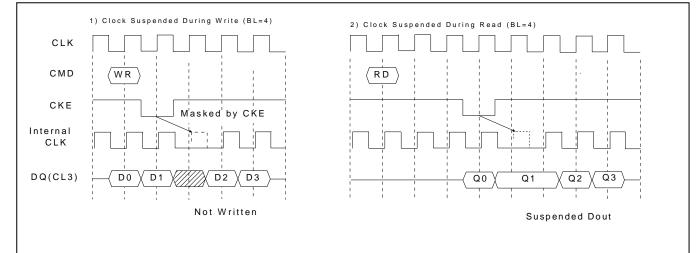
This command is not an execution command. No operations begin or terminate by this command.

CLK		
CKE	Н	
ਟਤ		
RAS		
CAS		
WE		
BA0, BA1 (Bank select)		
A10		
Add		
_		

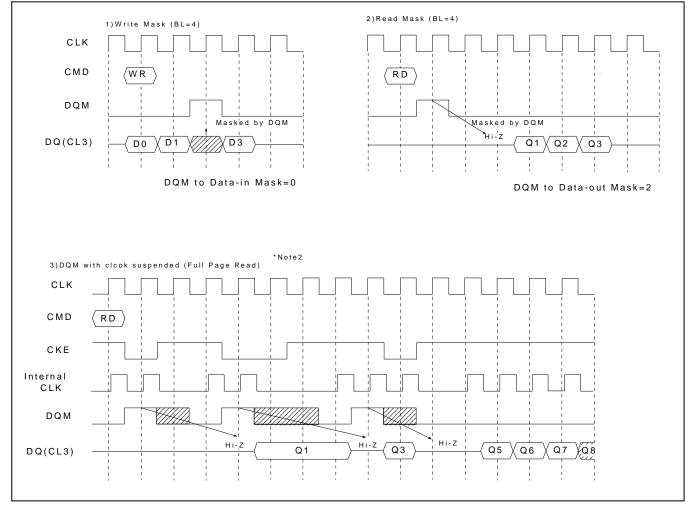
Fig. 10 No operation

BASIC FEATURE AND FUNCTION DESCRIPTIONS

1. CLOCK Suspend



2. DQM Operation



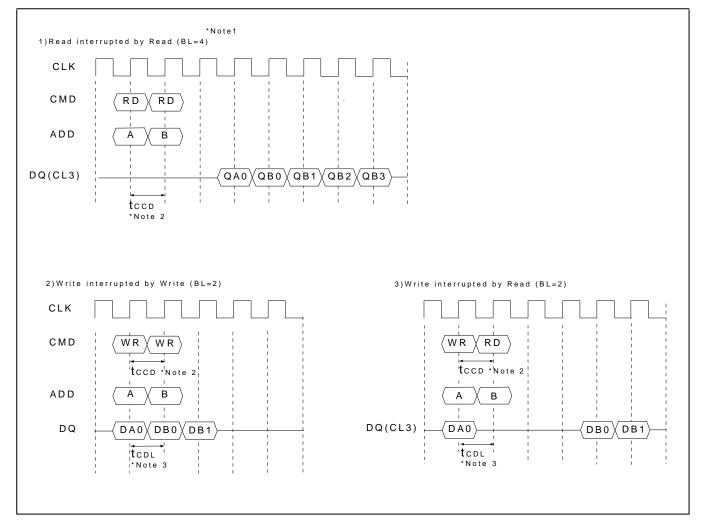
*Note: 1. CKE to CLK disable/enable = 1CLK.

2. DQM masks data out Hi-Z after 2CLKs which should masked by CKE "L".

3. DQM masks both data-in and data-out.



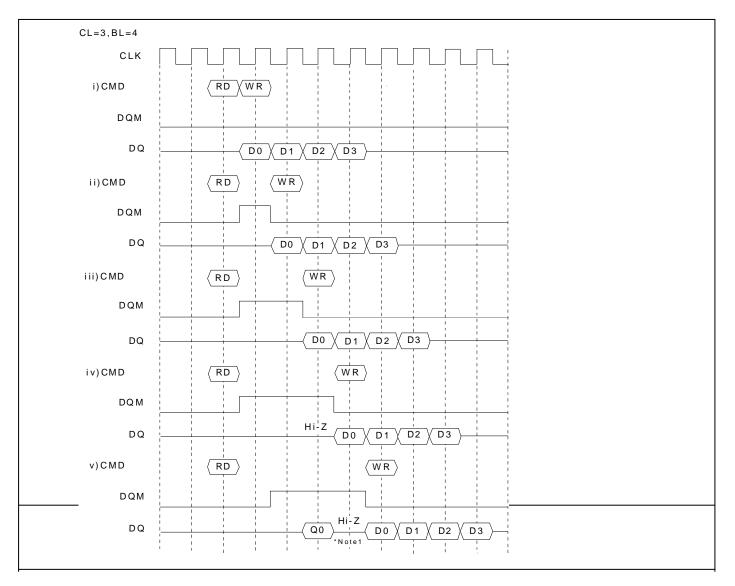
3. CAS Interrupt (I)



*Note: 1. By "interrupt" is meant to stop burst read/write by external before the end of burst.

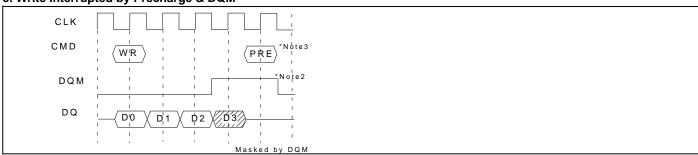
- By " \overline{CAS} interrupt ", to stop burst read/write by \overline{CAS} access; read and write.
- 2. tccd: \overline{CAS} to \overline{CAS} delay. (=1CLK)
- 3. tcpl: Last data in to new column address delay. (=1CLK)

4. CAS Interrupt (II): Read Interrupted by Write & DQM



*Note: 1. To prevent bus contention, there should be at least one gap between data in and data out.

5. Write Interrupted by Precharge & DQM

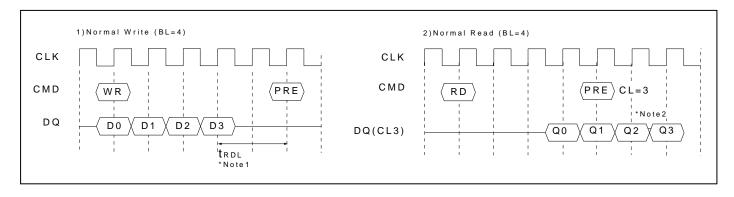


*Note: 1. To prevent bus contention, DQM should be issued which makes at least one gap between data in and data out. 2. To inhibit invalid write, DQM should be issued.

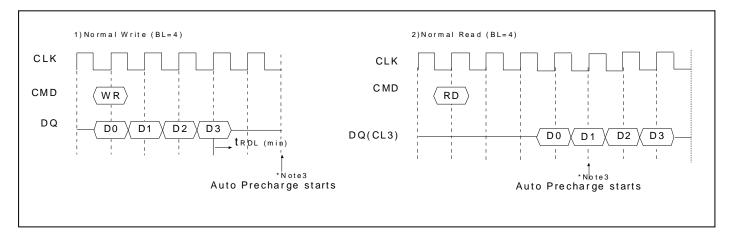
3. This precharge command and burst write command should be of the same bank, otherwise it is not precharge interrupt but only another bank precharge of four banks operation.



6. Precharge



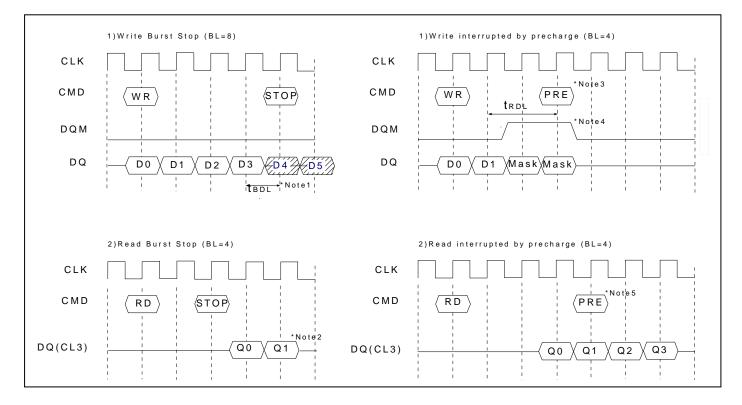
7. Auto Precharge



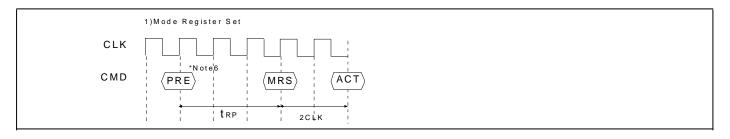
- *Note: 1. tRDL: Last data in to row precharge delay.
 - 2. Number of valid output data after row precharge: 2 for CAS Latency = 3 respectively.
 - 3. The row active command of the precharge bank can be issued after tree from this point. The new read/write command of other activated bank can be issued from this point. At burst read/write with auto precharge, CAS interrupt of the same/another bank is illegal.



8. Burst Stop & Interrupted by Precharge



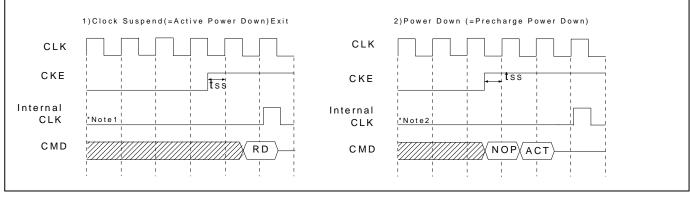
9. MRS



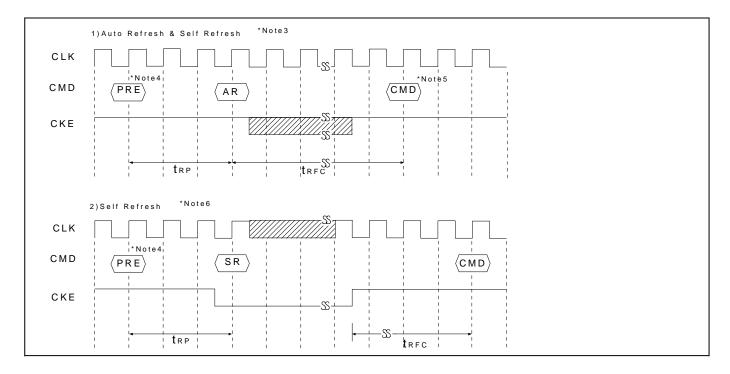
*Note: 1. tBDL: 1 CLK; Last data in to burst stop delay.

- Read or write burst stop command is valid at every burst length.
- 2. Number of valid output data after burst stop: 2 for CAS latency = 3 respectively.
- 3. Write burst is terminated. tRDL determinates the last data write.
- 4. DQM asserted to prevent corruption of locations D2 and D3.
- 5. Precharge can be issued here or earlier (satisfying tras min delay) with DQM.
- 6. PRE: All banks precharge, if necessary.
- MRS can be issued only at all banks precharge state.

10. Clock Suspend Exit & Power Down Exit



11. Auto Refresh & Self Refresh



*Note: 1. Active power down: one or more banks active state.

- 2. Precharge power down: all banks precharge state.
- The auto refresh is the same as CBR refresh of conventional DRAM. No precharge commands are required after auto refresh command. During tRFC from auto refresh command, any other command can not be accepted.
- 4. Before executing auto/self refresh command, all banks must be idle state.
- 5. MRS, Bank Active, Auto/Self Refresh, Power Down Mode Entry.
- 6. During self refresh entry, refresh interval and refresh operation are performed internally. After self refresh entry, self refresh mode is kept while CKE is low. During self refresh entry, all inputs expect CKE will be don't cared, and outputs will be in Hi-Z state. For the time interval of tRFC from self refresh exit command, any other command can not be accepted. 4K cycles of burst auto refresh is required immediately before self refresh entry and immediately after self refresh exit.



12. About Burst Type Control

Basic	Sequential Counting	At MRS A3 = "0". See the BURST SEQUENCE TABLE. (BL = 4,8) BL = 1, 2, 4, 8 and full page.
MODE	Interleave Counting	At MRS A3 = "1". See the BURST SEQUENCE TABLE. (BL = 4,8) BL = 4, 8 At BL = 1, 2 interleave Counting = Sequential Counting
		Every cycle Read/Write Command with random column address can realize
Random MODE	Random Column Access tccp = 1 CLK	Random Column Access.
		That is similar to Extended Data Out (EDO) Operation of conventional DRAM.

13. About Burst Length Control

	1	At MRS A210 = "000" At auto precharge. tras should not be violated.					
Basic	2	At MRS A210 = "001" At auto precharge. tras should not be violated.					
MODE	4	At MRS A210 = "010"					
	8	At MRS A210 = "011"					
	Full Page	At MRS A210 = "111" At the end of the burst length, burst is warp-around.					
Random MODE	Burst Stop	tBDL = 1, Valid DQ after burst stop is 2 for CAS latency 3 respectively. Using burst stop command, any burst length control is possible.					
Interrupt	RAS Interrupt (Interrupted by Precharge)	Before the end of burst. Row precharge command of the same bank stops read /write burst with auto precharge. tRDL = 2clk with DQM , Valid DQ after burst stop is 2 for CAS latency 3 respectively. During read/write burst with auto precharge, RAS interrupt can not be issued.					
MODE -	CAS Interrupt	Before the end of burst, new read/write stops read/write burst and starts new read/write burst. During read/write burst with auto precharge, CAS interrupt can not be issued.					

FUNCTION TRUTH TABLE (TABLE 1)

Current State	CS	RAS	CAS	WE	ВА	ADDR	ACTION	Note
	Н	Х	Х	Х	Х	Х	NOP	
	L	H	Н	Н	Х	Х	NOP	
	L	Н	Н	L	Х	Х	ILLEGAL	2
IDLE	L	Н	L	Х	BA	CA, A10/AP	ILLEGAL	2
	L	L	Н	Н	BA	RA	Row (&Bank) Active ; Latch RA	
	L	L	Н	L	BA	A10/AP	NOP	4
	L	L	L	Н	Х	Х	Auto Refresh or Self Refresh	5
	L	L	L	L	OP code	OP code	Mode Register Access	5
	Н	Х	Х	Х	Х	Х	NOP	
	L	Н	Н	Н	Х	Х	NOP	
	L	Н	Н	L	Х	Х	ILLEGAL	2
Row	L	H	L	Н	BA	CA, A10/AP	Begin Read ; latch CA ; determine AP	
Active	L	Н	L	L	BA	CA, A10/AP	Begin Write ; latch CA ; determine AP	
	L	L	Н	Н	BA	RA	ILLEGAL	2
	L	L	Н	L	BA	A10/AP	Precharge	
	L	L	L	Х	Х	Х	ILLEGAL	
	Н	Х	Х	Х	Х	Х	NOP (Continue Burst to End \rightarrow Row Active)	
	L	Н	Н	Н	Х	Х	NOP (Continue Burst to End \rightarrow Row Active)	
	L	Н	Н	L	Х	Х	Term burst → Row active	
Read	L	Н	L	Н	BA	CA, A10/AP	Term burst, New Read, Determine AP	
	L	Н	L	L	BA	CA, A10/AP	Term burst, New Write, Determine AP	3
	L	L	Н	Н	BA	RA	ILLEGAL	2
	L	L	Н	L	BA	A10/AP	Term burst, Precharge timing for Reads	
	L	L	L	Х	Х	X	ILLEGAL	
	Н	Х	Х	Х	Х	Х	NOP (Continue Burst to End \rightarrow Row Active)	
	L	Н	Н	Н	Х	Х	NOP (Continue Burst to End \rightarrow Row Active)	
	L	Н	Н	L	Х	Х	Term burst → Row active	
Write	L	Н	L	Н	BA	CA, A10/AP	Term burst, New Read, Determine AP	3
	L	Н	L	L	BA	CA, A10/AP	Term burst, New Write, Determine AP	3
	L	L	Н	H	BA	RA	ILLEGAL	2
		L	H	L	BA	A10/AP	Term burst, Precharge timing for Writes	3
		L	L	X	X	X	ILLEGAL	
	H	X	X	X	X	X	NOP (Continue Burst to End \rightarrow Row Active)	
Read with		H	H	H	X	X	NOP (Continue Burst to End → Row Active)	
Auto	L	Н	н	L	X	X	ILLEGAL	
Precharge		Н		X	BA	CA, A10/AP	ILLEGAL	
ricenarge		L	H	X	BA	RA, RA10	ILLEGAL	2
		L	L	X	X	X	ILLEGAL	2
	<u> </u>	X	X	X	X	× ×	NOP (Continue Burst to End \rightarrow Row Active)	
Write with	 	Ĥ	Ĥ	Ĥ	X	X	NOP (Continue Burst to End \rightarrow Row Active)	
Auto		H	H		X	<u>х</u>	ILLEGAL	
Precharge	<u>L</u>	H		X	BA	CA, A10/AP	ILLEGAL	
riecharge	 L	L	H	X	BA BA	RA, RA10	ILLEGAL	2
	L	L	H L	X	Х	X X	ILLEGAL	2

Current State	CS	RAS	CAS	WE	ВА	ADDR	ACTION	Note
	Н	Х	Х	Х	Х	Х	NOP \rightarrow Idle after t _{RP}	
	L	Н	Н	Н	Х	Х	NOP \rightarrow Idle after t _{RP}	
Precharging	L	Н	Н	L	Х	Х	ILLEGAL	2
	L	Н	L	Х	BA	CA	ILLEGAL	2
	L	L	Н	Н	BA	RA	ILLEGAL	2
	L	L	Н	L	BA	A10/AP	NOP \rightarrow Idle after t _{RP}	4
	L	L	L	Х	Х	Х	ILLEGAL	
	Н	Х	Х	Х	Х	Х	NOP \rightarrow Row Active after t _{RCD}	
	L	Н	Н	Н	Х	Х	NOP \rightarrow Row Active after t _{RCD}	
Row	L	Н	Н	L	Х	Х	ILLEGAL	2
Activating	L	Н	L	Х	BA	CA	ILLEGAL	2
_	L	L	Н	Н	BA	RA	ILLEGAL	2
	L	L	Н	L	BA	A10/AP	ILLEGAL	2
	L	L	L	Х	Х	Х	ILLEGAL	
	Н	Х	Х	Х	Х	Х	NOP \rightarrow Idle after t _{RFC}	
	L	Н	Н	Х	Х	Х	NOP \rightarrow Idle after t _{RFC}	
Refreshing	L	Н	L	Х	Х	Х	ILLEGAL	
_	L	L	Н	Х	Х	Х	ILLEGAL	
	L	L	L	Х	Х	Х	ILLEGAL	
	Н	Х	Х	Х	Х	Х	NOP \rightarrow Idle after 2clocks	
Mode	L	Н	Н	Н	Х	Х	NOP \rightarrow Idle after 2clocks	
Register	L	Н	Н	L	Х	Х	ILLEGAL	
Accessing	L	Н	L	Х	Х	Х	ILLEGAL	
	L	L	Х	Х	Х	Х	ILLEGAL	

Abbreviations:

RA = Row Address NOP = No Operation Command BA = Bank Address CA = Column Address

AP = Auto Precharge

*Note: 1. All entries assume the CKE was active (High) during the precharge clock and the current clock cycle.

2. Illegal to bank in specified state; Function may be legal in the bank indicated by BA, depending on the state of the bank.

3. Must satisfy bus contention, bus turn around, and/or write recovery requirements.

4. NOP to bank precharge or in idle state. May precharge bank indicated by BA (and A10/AP).

5. Illegal if any bank is not idle.

FUNCTION TRUTH TABLE (TABLE2)

Current State	CKE (n-1)	CKE n	\overline{cs}	RAS		WE	ADDR	ACTION	Note
	Н	Х	Х	Х	Х	Х	Х	INVALID	
	L	Н	Н	Х	Х	Х	Х	Exit Self Refresh \rightarrow Idle after t _{RFC} (ABI)	6
Self	L	Н	L	Н	Н	Н	Х	Exit Self Refresh \rightarrow Idle after t _{RFC} (ABI)	6
Refresh	L	Н	L	Н	Н	L	Х	ILLEGAL	
	L	Н	L	Н	L	Х	Х	ILLEGAL	
	L	Н	L	L	Х	Х	Х	ILLEGAL	
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Self Refresh)	
	Н	Х	Х	Х	Х	Х	Х	INVALID	
All	L	Н	Н	Х	Х	Х	Х	Exit Self Refresh → ABI	7
Banks	L	Н	L	Н	Н	Н	Х	Exit Self Refresh → ABI	7
Precharge	L	Н	L	Н	Н	L	Х	ILLEGAL	
Power	L	Н	L	Н	L	Х	Х	ILLEGAL	
Down	L	Н	L	L	Х	Х	Х	ILLEGAL	
	L	L	Х	Х	Х	Х	Х	NOP (Maintain Low Power Mode)	
	Н	Н	Х	Х	Х	Х	Х	Refer to Table1	
	Н	L	Н	Х	Х	Х	Х	Enter Power Down	8
	Н	L	L	Н	H	Н	Х	Enter Power Down	8
All	Н	L	L	Н	Н	L	Х	ILLEGAL	
Banks	Н	L	L	Н	L	Х	Х	ILLEGAL	
Idle	Н	L	L	L	Н	Н	RA	Row (& Bank) Active	
	Н	L	L	L	L	Н	Х	Enter Self Refresh	8
	Н	L	L	L	L	L	OP Code	Mode Register Access	
	L	L	Х	Х	Х	Х	Х	NOP	
Any State	Н	Н	Х	Х	Х	Х	Х	Refer to Operations in Table 1	
other than	Н	L	Х	Х	Х	Х	Х	Begin Clock Suspend next cycle	9
Listed	L	Н	Х	Х	Х	Х	Х	Exit Clock Suspend next cycle	9
above	L	L	Х	Х	Х	Х	Х	Maintain Clock Suspend	

Abbreviations: ABI = All Banks Idle, RA = Row Address

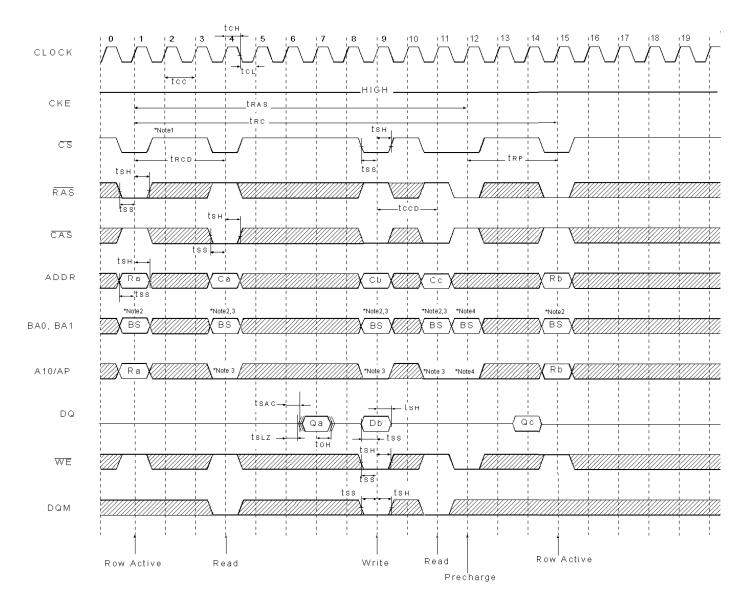
*Note: 6.CKE low to high transition is asynchronous.

7.CKE low to high transition is asynchronous if restart internal clock.

A minimum setup time 1CLK + tss must be satisfy before any command other than exit. 8.Power down and self refresh can be entered only from the all banks idle state.

9.Must be a legal command.

Single Bit Read-Write-Read Cycle (Same Page) @ CAS Latency = 3, Burst Length = 1



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Note: 1. All input expect CKE & DQM can be don't care when \overline{CS} is high at the CLK high going edge.

2. Bank active @ read/write are controlled by BA0~BA1.

BA1	BA0	Active & Read/Write
0	0	Bank A
0	1	Bank B
1	0	Bank C
1	1	Bank D

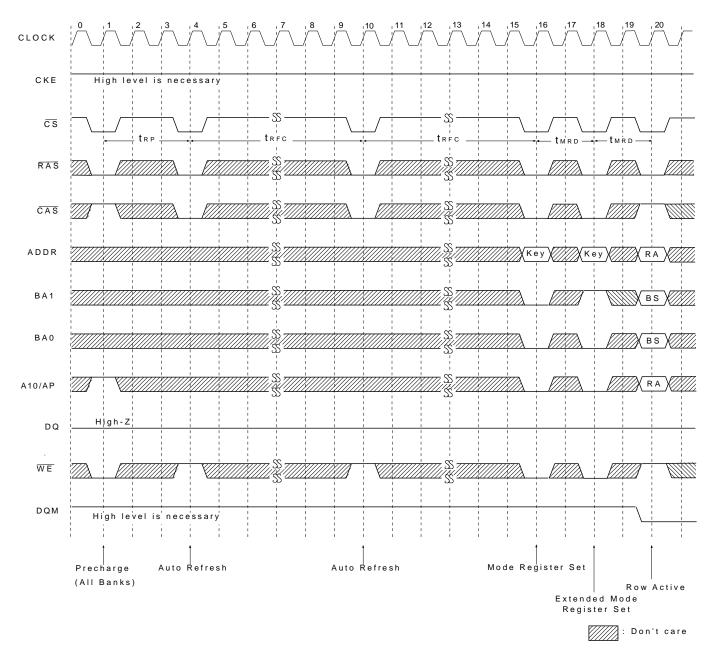
3. Enable and disable auto precharge function are controlled by A10/AP in read/write command

A10/AP	BA1	BA0	Operating			
	0	0	Disable auto precharge, leave A bank active at end of burst.			
0	0	1	Disable auto precharge, leave B bank active at end of burst.			
	1	0	Disable auto precharge, leave C bank active at end of burst.			
	1	1	Disable auto precharge, leave D bank active at end of burst.			
	0	0	Enable auto precharge, precharge bank A at end of burst.			
1	0	1	Enable auto precharge, precharge bank B at end of burst.			
	1	0	Enable auto precharge, precharge bank C at end of burst.			
	1	1	Enable auto precharge, precharge bank D at end of burst.			

4. A10/AP and BA0~BA1 control bank precharge when precharge is asserted.

A10/AP	BA1	BA0	Precharge
0	0	0	Bank A
0	0	1	Bank B
0	1	0	Bank C
0	1	1	Bank D
1	Х	Х	All Banks

Power Up Sequence

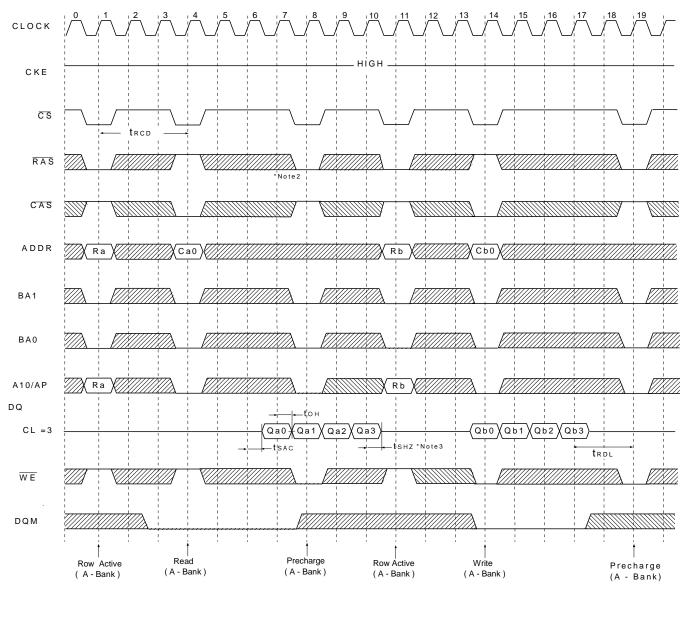


Power-Up and Initialization Sequence

The following sequence is required for POWER UP and Initialization.

- 1. Apply power and attempt to maintain CKE at a low state (all other inputs may be undefined.)
- Apply V_{DD} before or at the same time as V_{DDQ}
 - Apply V_{DDQ}
- 2. Start clock and maintain stable condition for a minimum.
- 3. The minimum of 200us after stable power and clock (CLK), apply NOP & take CKE high.
- 4. Issue precharge commands for all banks of the device.
- 5. Issue 2 or more auto-refresh commands.
- 6. Issue mode register set command to initialize the mode register.
- 7. Issue extended mode register set command to set PASR and DS.

Read & Write Cycle at Same Bank @ Burst Length = 4



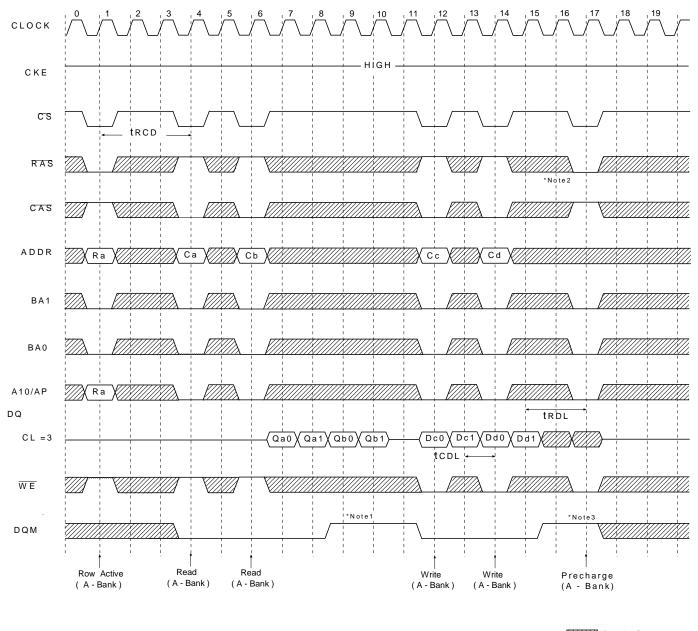
:Don't Care

*Note:

: 1. Minimum row cycle times is required to complete internal DRAM operation.

- 2. Row precharge can interrupt burst on any cycle. [CAS Latency-1] number of valid output data is available after Row precharge. Last valid output will be Hi-Z (tsHz) after the clock.
- 3. Output will be Hi-Z after the end of burst. (1, 2, 4, 8 & Full page bit burst)

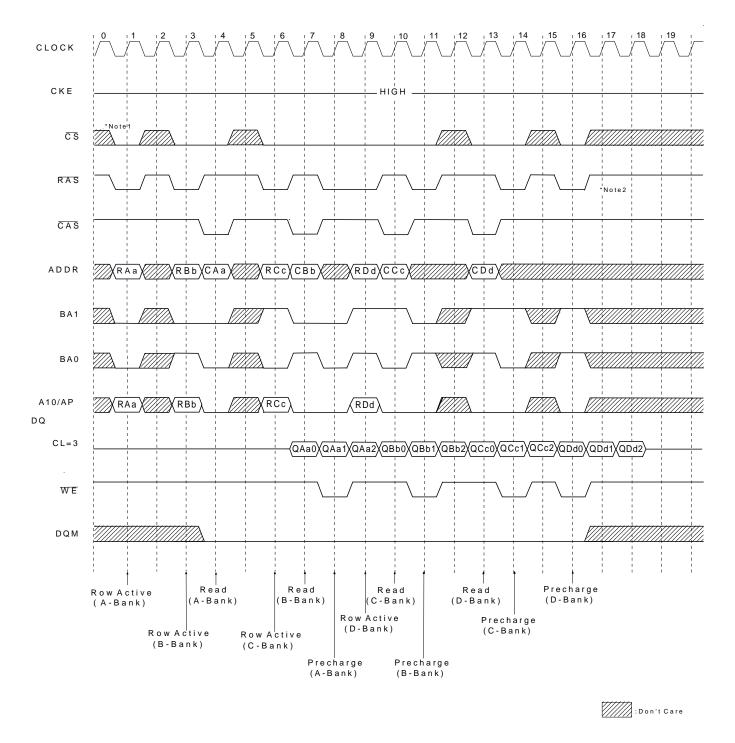
Page Read & Write Cycle at Same Bank @ Burst Length = 4



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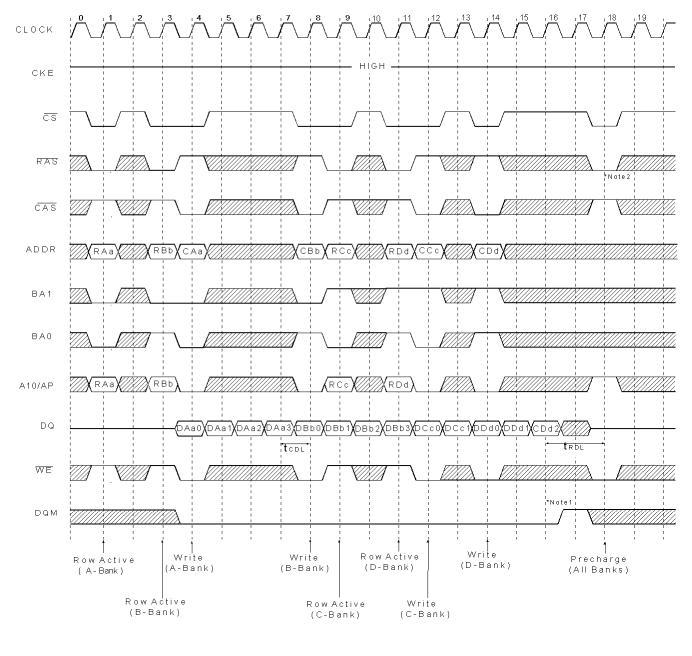
- Note: 1. To Write data before burst read ends. DQM should be asserted three cycles prior to write command to avoid bus contention.
 - 2. Row precharge will interrupt writing. Last data input, tRDL before row precharge, will be written.
 - 3. DQM should mask invalid input data on precharge command cycle when asserting precharge before end of burst. Input data after Row precharge cycle will be masked internally.

Page Read Cycle at Different Bank @ Burst Length = 4



Note: 1. $\overline{\text{CS}}$ can be don't cared when $\overline{\text{RAS}}$, $\overline{\text{CAS}}$ and $\overline{\text{WE}}$ are high at the clock high going edge. 2. To interrupt a burst read by row precharge, both the read and the precharge banks must be the same.

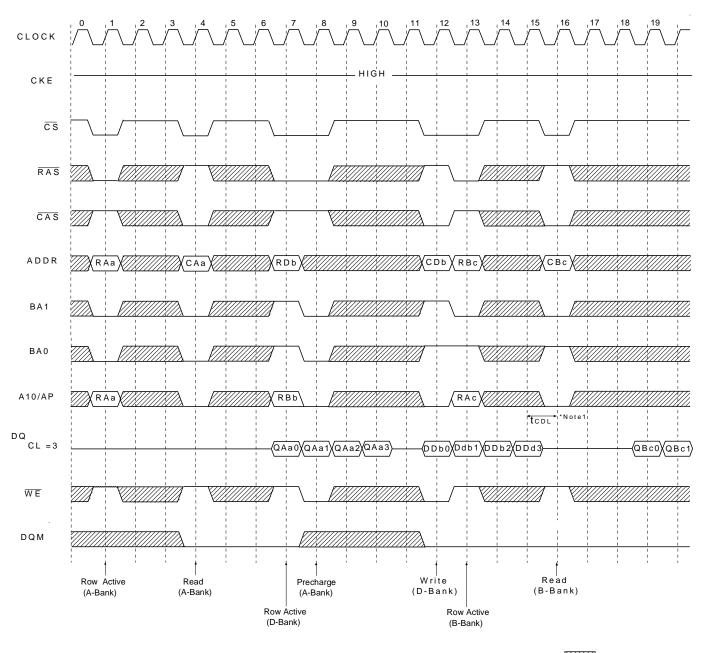
Page Write Cycle at Different Bank @ Burst Length = 4



: Don't care

*Note: 1. To interrupt burst write by Row precharge, DQM should be asserted to mask invalid input data. 2. To interrupt burst write by Row precharge, both the write and the precharge banks must be the same.

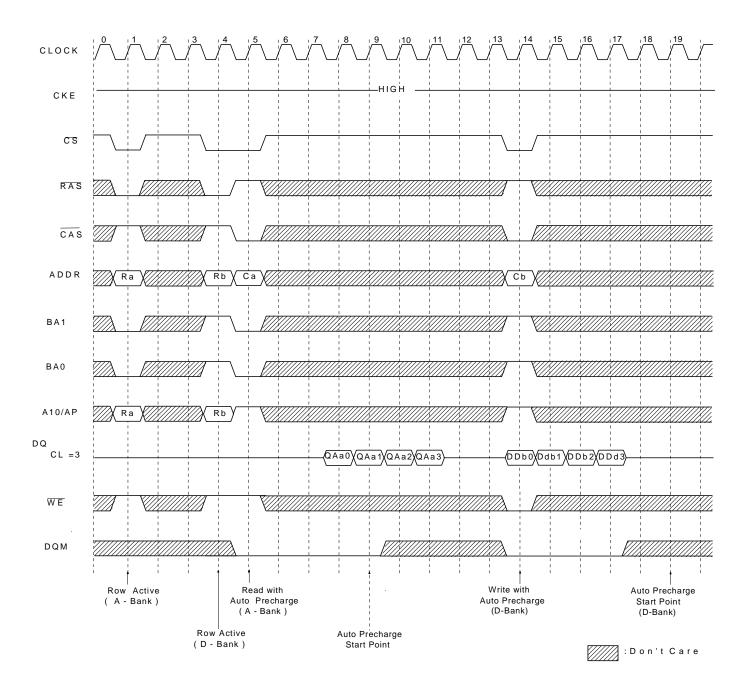
Read & Write Cycle at Different Bank @ Burst Length = 4



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*Note: 1. tcpL should be met to complete write.

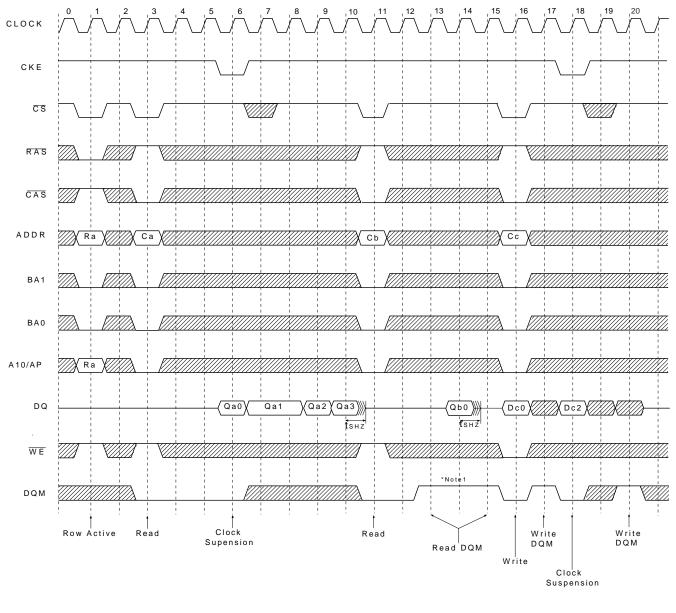
Read & Write cycle with Auto Precharge @ Burst Length = 4



*Note: 1. tcpL should be controlled to meet minimum tras before internal precharge start. (In the case of Burst Length = 1 & 2)

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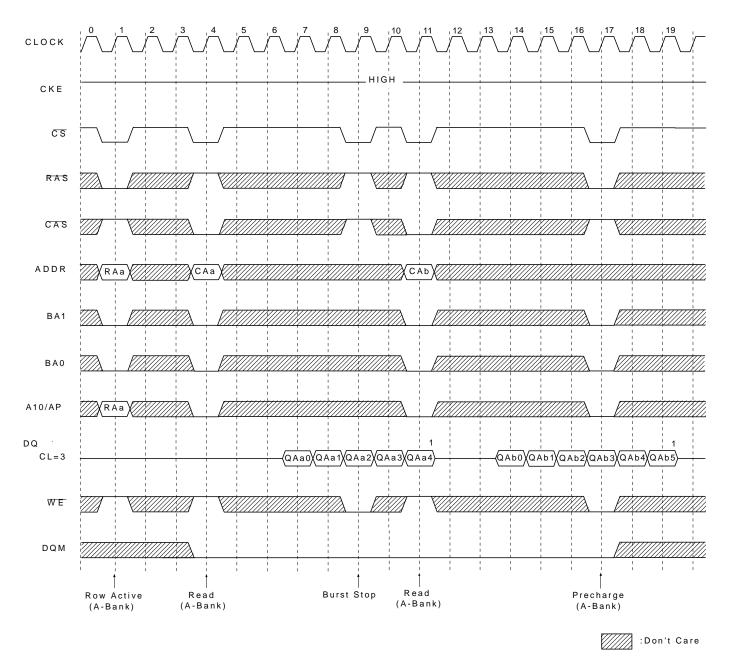
Clock Suspension & DQM Operation Cycle @ CAS Latency = 3, Burst Length = 4



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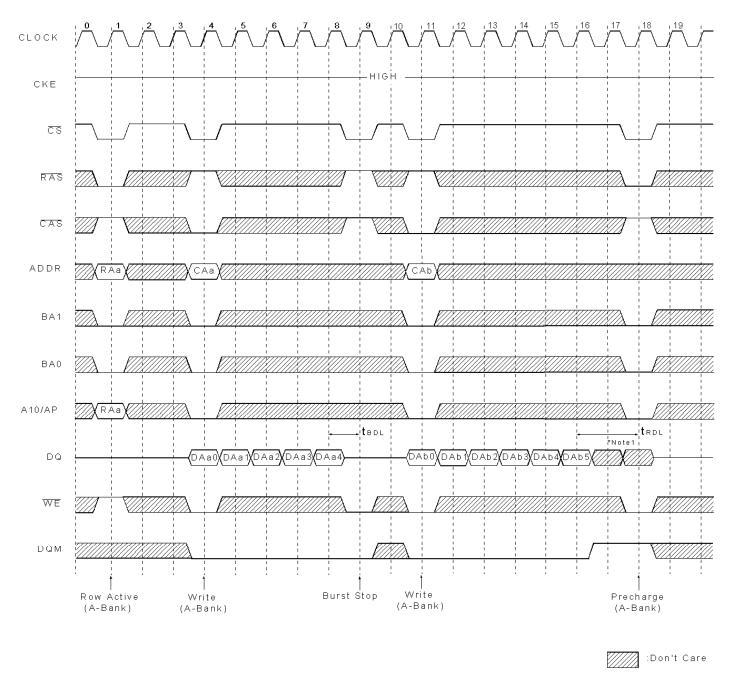
*Note: 1. DQM is needed to prevent bus contention

Read interrupted by Precharge Command & Read Burst Stop Cycle @ Burst Length = Full page



- *Note: 1. About the valid DQs after burst stop, it is same as the case of RAS interrupt. This case is illustrated above timing diagram. See the label 1. But at burst write, Burst stop and RAS interrupt should be compared carefully. Refer the timing diagram of "Full page write burst stop cycles".
 - 2. Burst stop is valid at every burst length.

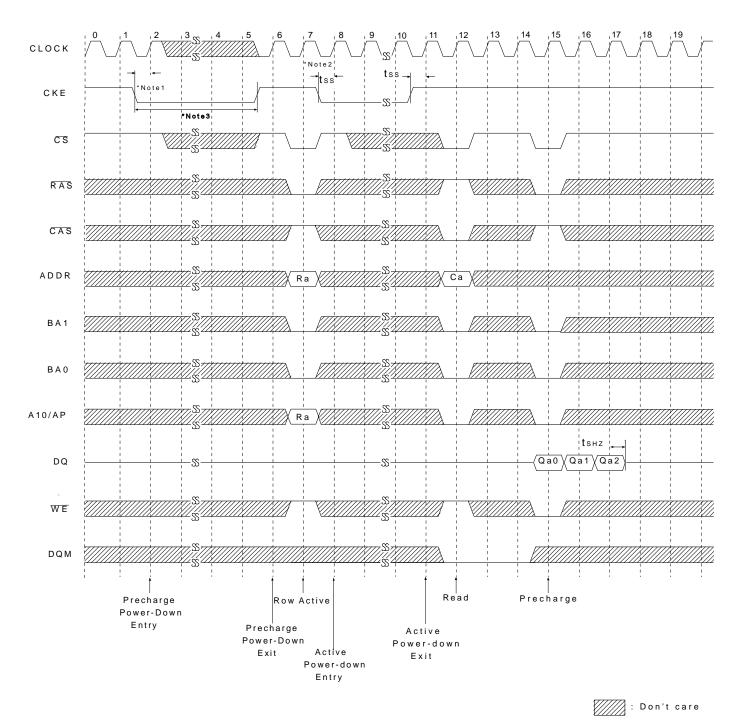
Write interrupted by Precharge Command & Write Burst Stop Cycle @ Burst Length = Full page



*Note: 1. Data-in at the cycle of interrupted by precharge can not be written into the corresponding memory cell. It is defined by AC parameter of tRDL.

- DQM at write interrupted by precharge command is needed to prevent invalid write.
- DQM should mask invalid input data on precharge command cycle when asserting precharge before end of burst. Input data after Row precharge cycle will be masked internally.
- 2. Burst stop is valid at every burst length.

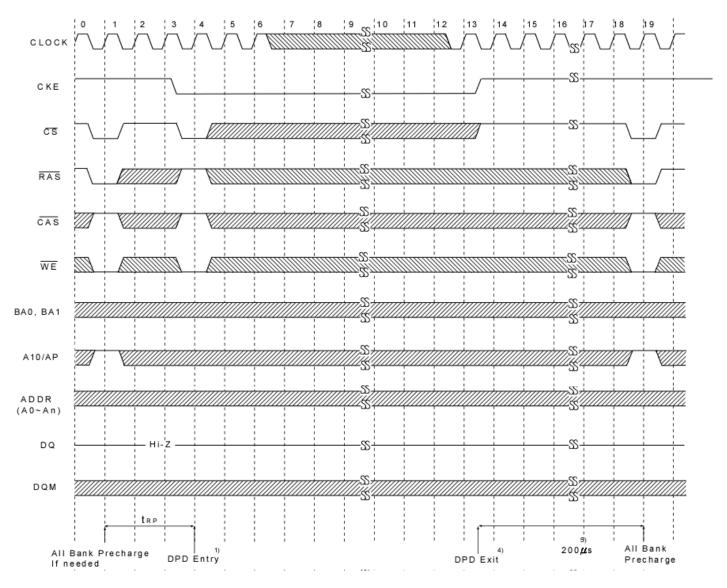
Active/Precharge Power Down Mode @ CAS Latency = 3, Burst Length = 4



*Note: 1. All banks should be in idle state prior to entering precharge power down mode.

- 2. CKE should be set high at least 1CLK + tss prior to Row active command.
- 3. Can not violate minimum refresh specification. (64ms)

Deep Power Down Mode Entry & Exit Cycle



Note:

DEFINITION OF DEEP POWER MODE FOR Mobile SDRAM:

Deep Power Down Mode is an operating mode to achieve maximum power reduction by cutting the power of the whole memory of the device. Once the device enters in Deep Power Down Mode, data will not be retained. Full initialization is required when the device exits from Deep Power Down Mode.

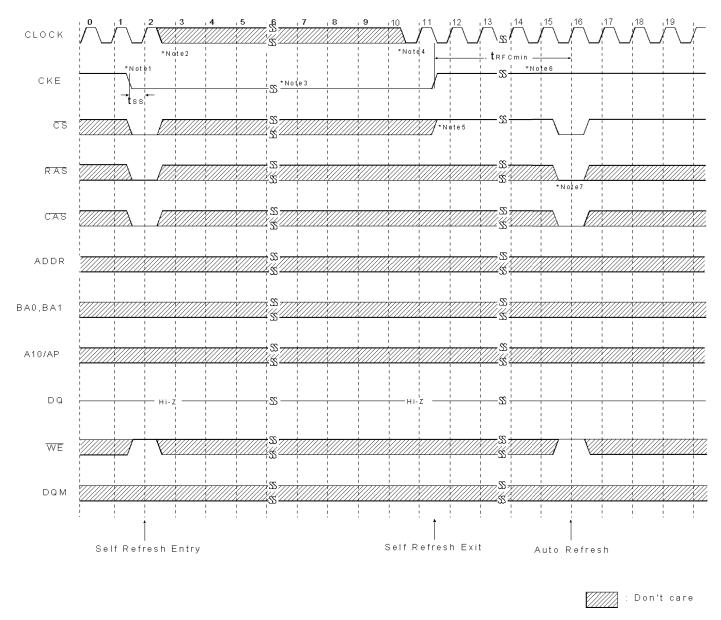
TO ENTER DEEP POWER DOWN MODE

- 1) The deep power down mode is entered by having \overline{CS} and \overline{WE} held low with \overline{RAS} and \overline{CAS} high at the rising edge of the clock. While CKE is low.
- 2) Clock must be stable before exited deep power down mode.
- 3) Device must be in the all banks idle state prior to entering Deep Power Down mode.

TO EXIT DEEP POWER DOWN MODE

- 4) The deep power down mode is exited by asserting CKE high.
- 5) 200 μ s wait time is required to exit from Deep Power Down.
- 6) Upon exiting deep power down an all bank precharge command must be issued followed by two auto refresh commands and a load mode register sequence.

Self Refresh Entry & Exit Cycle



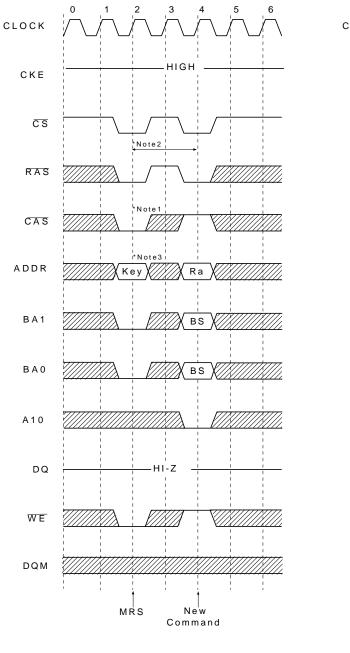
*Note: TO ENTER SELF REFRESH MODE

- 1. CS, RAS & CAS with CKE should be low at the same clock cycle.
- 2. After 1 clock cycle, all the inputs including the system clock can be don't care except for CKE.
- 3. The device remains in self refresh mode as long as CKE stays "Low".
- cf.) Once the device enters self refresh mode, minimum tras is required before exit from self refresh.

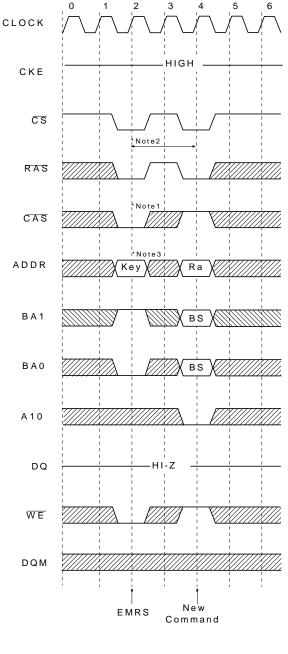
TO EXIT SELF REFRESH MODE

- 4. System clock restart and be stable before returning CKE high.
- 5. $\overline{\text{CS}}$ starts from high.
- 6. Minimum tRFC is required after CKE going high to complete self refresh exit.
- 7. 4K cycles of burst auto refresh is required immediately before self refresh entry and immediately after self refresh exit.

Mode Register Set Cycle



Extended Mode Register Set Cycle



All banks precharge should be completed before Mode Register Set cycle and auto refresh cycle.

MODE REGISTER SET CYCLE

- *Note: 1. \overline{CS} , \overline{RAS} , \overline{CAS} , & \overline{WE} activation at the same clock cycle with address key will set internal mode register.
 - 2. Minimum 2 clock cycles should be met before new \overline{RAS} activation.
 - 3. Please refer to Mode Register Set table.

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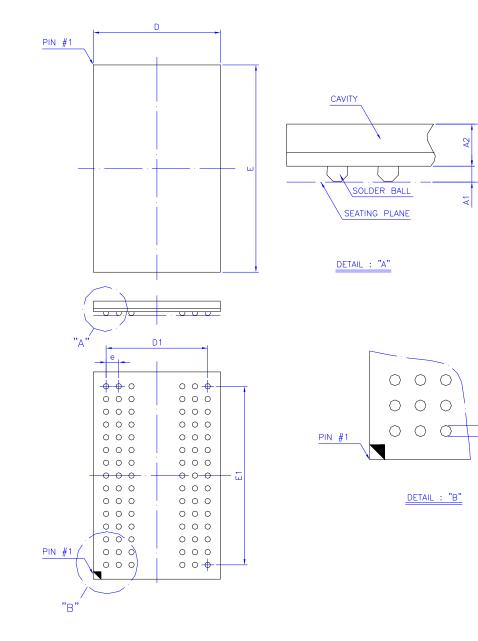


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PACKING DIMENSIONS

90-BALL SDRAM (8x13 mm)



Symbol	Dim	ension in	mm	Dimension in inch			
	Min	Norm	Max	Min	Norm	Max	
Α			1.20			0.047	
A ₁	0.30	0.35	0.40	0.012	0.014	0.016	
A ₂		0.586			0.023		
Øb	0.40	0.45	0.50	0.016	0.018	0.020	
D	7.90	8.00	8.10	0.311	0.315	0.319	
E	12.90	13.00	13.10	0.508	0.512	0.516	
D ₁		6.40			0.252		
E ₁		11.20			0.441		
е		0.80			0.031		

Controlling dimension : Millimeter.

Revision History

Revision	Date	Description
0.1	2011.11.24	Original
0.2	2012.06.22	 Delete CAS Latency: 2 Correct the figure of Deep Power Down Mode Entry & Exit Cycle
1.0	2014.02.21	 Delete "Preliminary" Modify the specification of I_{CC2NS}, I_{CC3PS}, I_{CC3PS}, I_{CC3NS}

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